

## N-Channel 60V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a, e</sup>	Q <sub>g</sub> (Typ)		
60	$0.0023$ at $V_{GS} = 10 \text{ V}$	100	61nC		
	0.0032 at V <sub>GS</sub> = 4.5 V	90	OIIIC		

#### **FEATURES**

- TrenchFET® Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested
   Compliant to RoHS Directive 2011/65/EU

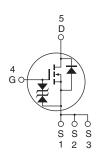


#### **APPLICATIONS**

- OR-ing
- Server
- DC/DC



1, 2, 3 Source Gate Drain



Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V <sub>DS</sub>	60	V		
Gate-Source Voltage	V <sub>GS</sub>	± 20	v		
	T <sub>C</sub> = 25 °C		100 <sup>a, e</sup>	A	
Continuous Drain Current (T. – 175 °C)	T <sub>C</sub> = 70 °C	,	85 <sup>e</sup>		
Continuous Drain Current (T <sub>J</sub> = 175 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	35.8 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		27 <sup>b, c</sup>		
Pulsed Drain Current		I <sub>DM</sub>	275		
Avalanche Current Pulse  Single Pulse Avalanche Energy  L = 0.1 mH		I <sub>AS</sub>	39		
		E <sub>AS</sub>	94.8	mJ	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I <sub>S</sub>	100 <sup>a, e</sup>	Α	
Continuous Source-Diam blode Current	T <sub>A</sub> = 25 °C	'S	3.13 <sup>b, c</sup>		
	T <sub>C</sub> = 25 °C		135 <sup>a</sup>		
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	95	14/	
	T <sub>A</sub> = 25 °C	' D	3.75 <sup>b, c</sup>	W	
	T <sub>A</sub> = 70 °C		2.63 <sup>b, c</sup>		
Operating Junction and Storage Temperature Ra	ange	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Тур.	Max.	Unit	
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 sec	R <sub>thJA</sub>	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R <sub>thJC</sub>	0.5	0.6	C/VV	

#### Notes:

- a. Based on T<sub>C</sub> = 25 °C.
  b. Surface mounted on 1" x 1" FR4 board.

- b. Striate informed on 1 X 1 114 board.
  c. t = 10 sec.
  d. Maximum under steady state conditions is 90 °C/W.
  e. Calculated based on maximum junction temperature. Package limitation current is 90 A.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 250 \		35		>//00
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250  \mu A$		- 7.5		mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.5		2.5	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	1
	IDSS	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μA
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	100			Α
Drain-Source On-State Resistance <sup>a</sup>		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 38.8 A		0.0023		
	R <sub>DS(on)</sub>	$V_{GS} = 4.5 \text{ V}, I_D = 37 \text{ A}$		0.0032		Ω
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 38.8 A		160		S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>			5801		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1825		
Reverse Transfer Capacitance	C <sub>rss</sub>			1070		
Total Gate Charge	Qg	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 38.8 \text{ A}$		92	157	nC
				61	87	
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 28.8 \text{ A}$		44		
Gate-Drain Charge	Q <sub>gd</sub>			29		
Gate Resistance	R <sub>g</sub>	f = 1 MHz		1.4	2.1	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			18	27	ns
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 0.625 $\Omega$		11	17	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong 24$ A, $V_{GEN}$ = 10 V, $R_g$ = 1 $\Omega$		70	105	
Fall Time	t <sub>f</sub>			10	15	
Turn-On Delay Time	t <sub>d(on)</sub>			55	83	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 0.67 $\Omega$		180	270	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong 22.5$ A, $V_{GEN}$ = 4.5 V, $R_g$ = 1 $\Omega$		55	83	
Fall Time	t <sub>f</sub>			12	18	
<b>Drain-Source Body Diode Characteristic</b>	cs					
Continuous Source-Drain Diode Current	I <sub>S</sub>	$T_C = 25  ^{\circ}C$			120	A
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				120	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 22 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	L = 20 A di/dt = 100 A/vp T = 25 °C		52	78	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			70.2	105	nC
Reverse Recovery Fall Time t		$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		27		
Reverse Recovery Rise Time	t <sub>b</sub>			25		ns

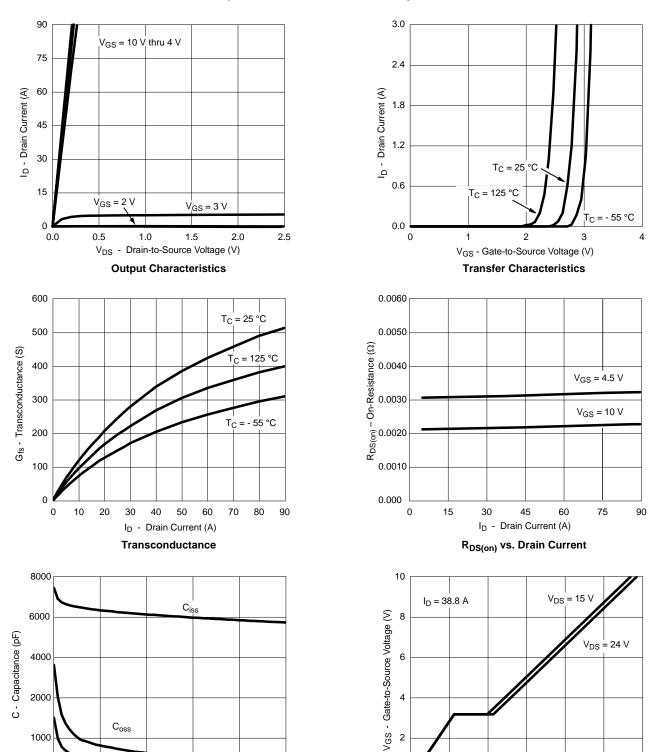
#### Notes:

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



服务热线:400-655-8788

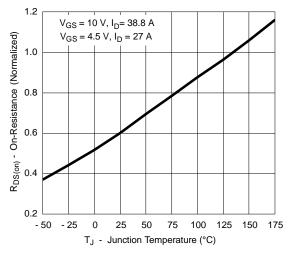
 $C_{rss}$ 

Q<sub>g</sub> - Total Gate Charge (nC)

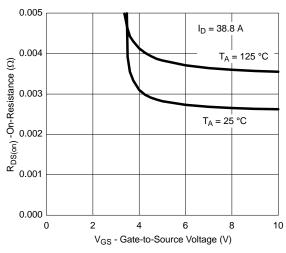
**Gate Charge** 



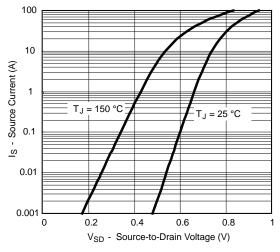
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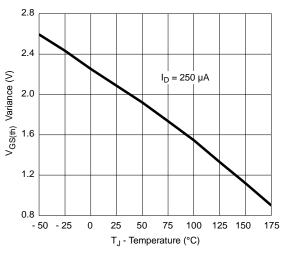
On-Resistance vs. Junction Temperature



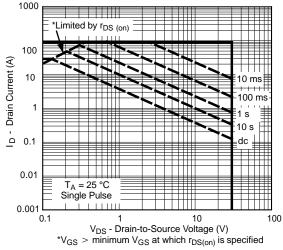
 $R_{DS(on)}$  vs.  $V_{GS}$  vs. Temperature



Forward Diode Voltage vs. Temperature



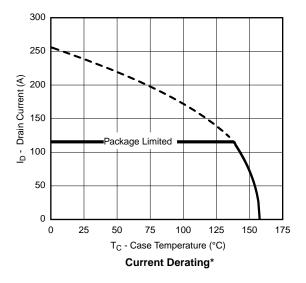
Threshold Voltage

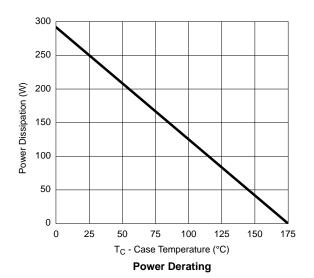


Safe Operating Area, Junction-to-Ambient

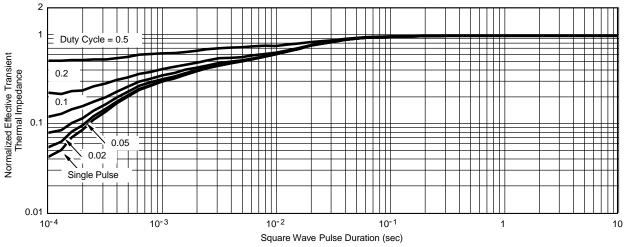


#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





\*The power dissipation  $P_D$  is based on  $T_{J(max)}$  = 175 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

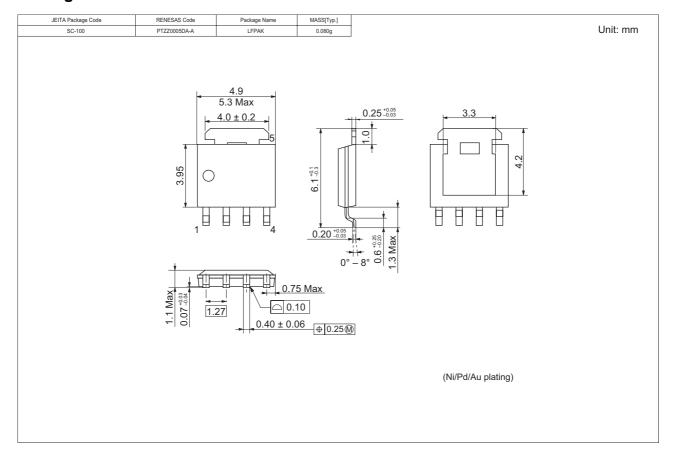


Normalized Thermal Transient Impedance, Junction-to-Case

6



### **Package Dimensions**





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